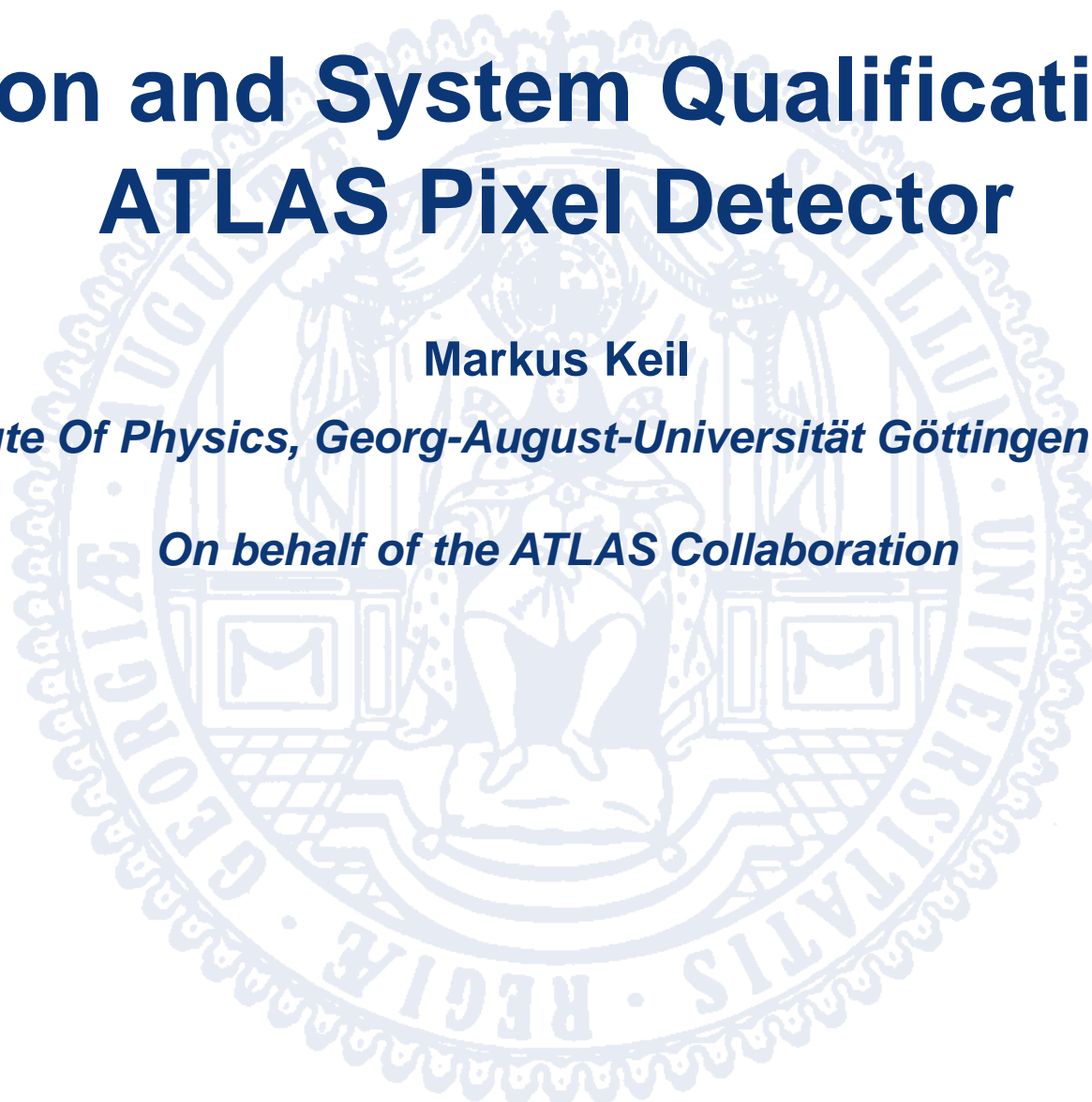


Integration and System Qualification of the ATLAS Pixel Detector

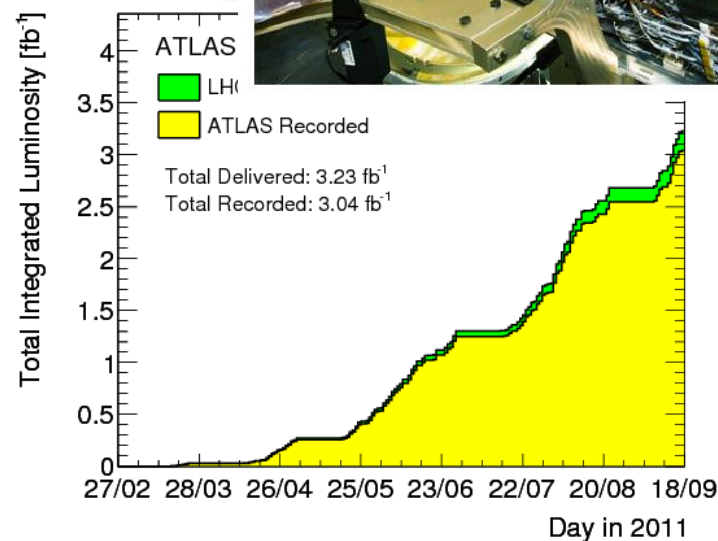
Markus Keil

2nd Institute Of Physics, Georg-August-Universität Göttingen and CERN

On behalf of the ATLAS Collaboration



- Will cover the period from integration to operation
 - Mainly QC
- Will try to focus on lessons we have learned
 - Do not claim to have brand-new insights, but rather summarise the well-known pitfalls we encountered
 - Recommendations will be based on the assumption of infinite time; it is clear that in some cases the perfect QA might have to be sacrificed to the schedule
 - (I will also mention a few things that were successful ;-))



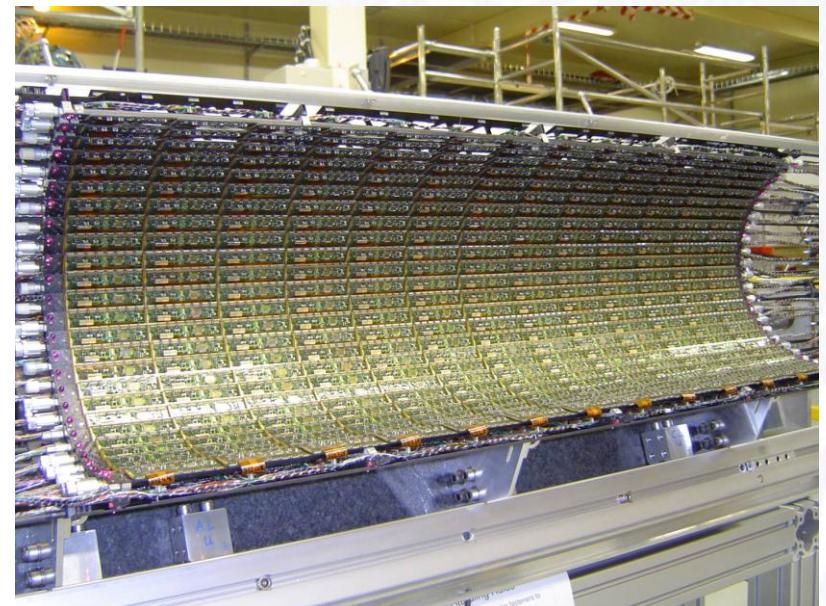
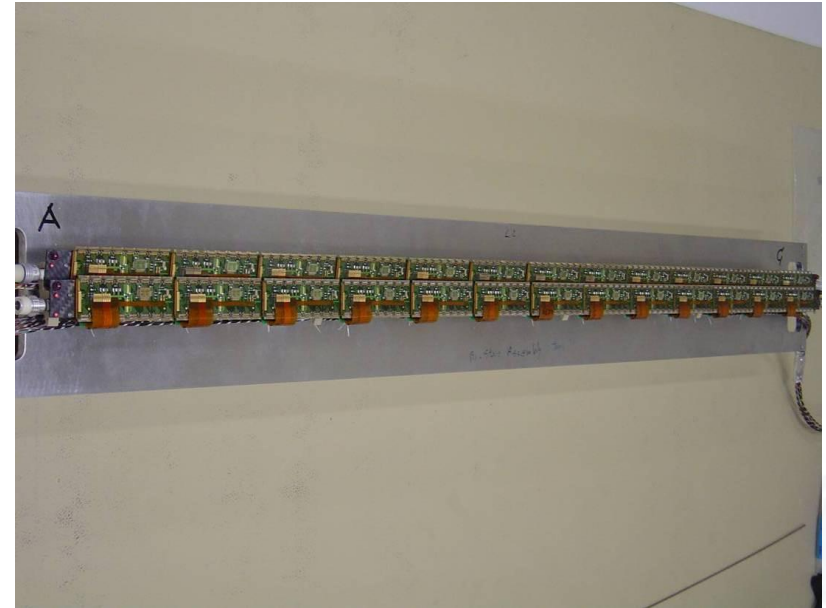
- Pixel Detector Integration
- Pixel Package Integration
- Pixel Detector Installation
- Pixel Detector Operation
- Conclusions



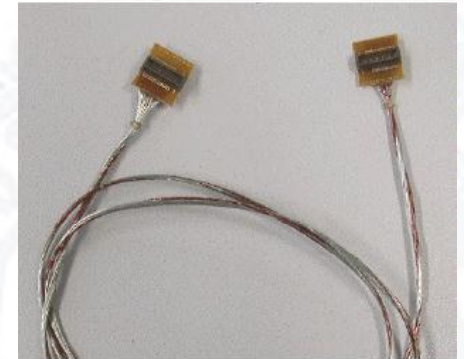
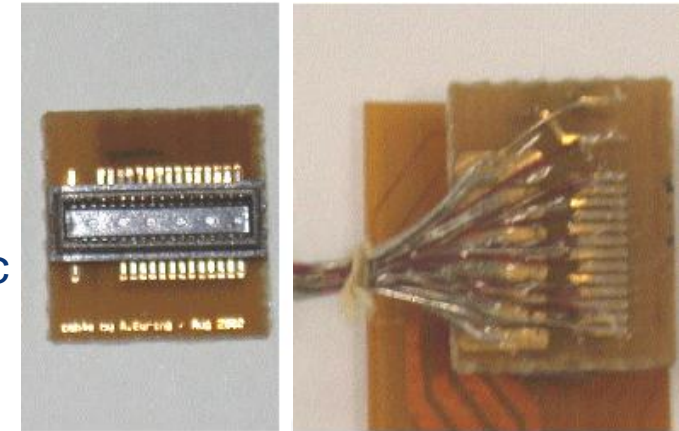
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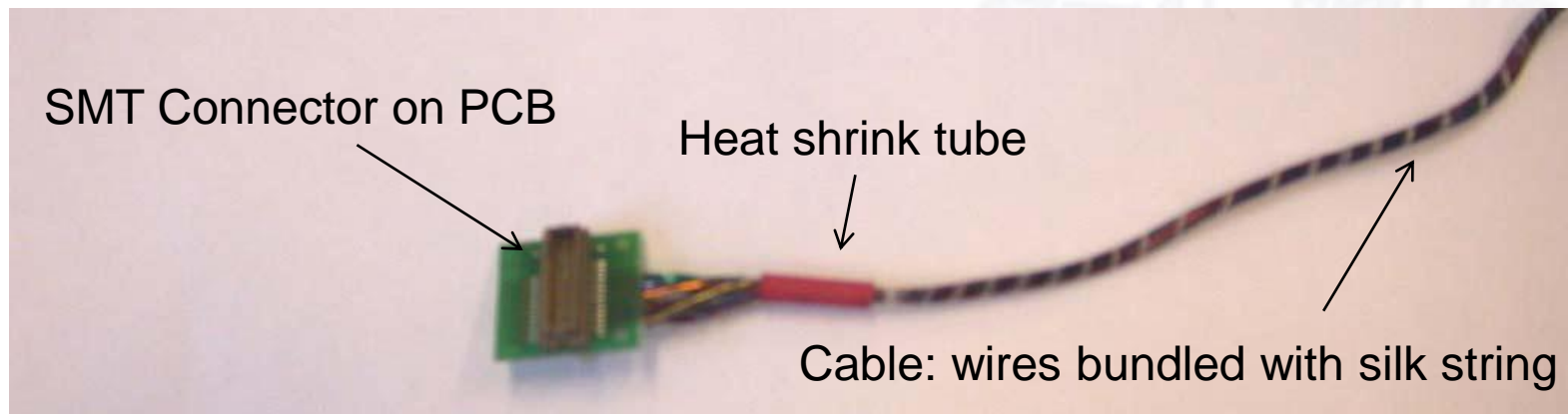
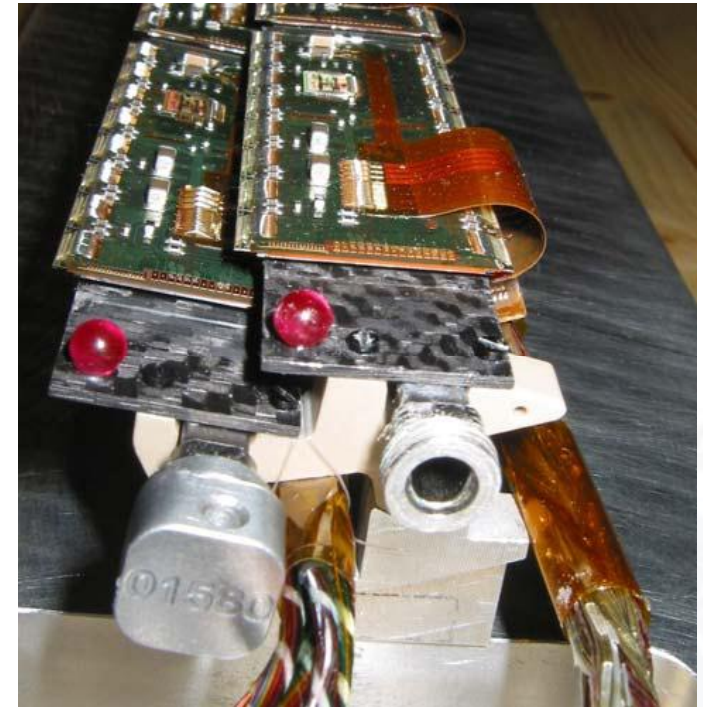
- Staves were mounted to bi-staves (cooling unit)
- Bi-staves were mounted into half-shells
- Half-shells were clamped together
- During bi-stave construction:
Test of several modules at a time with dedicated test setup



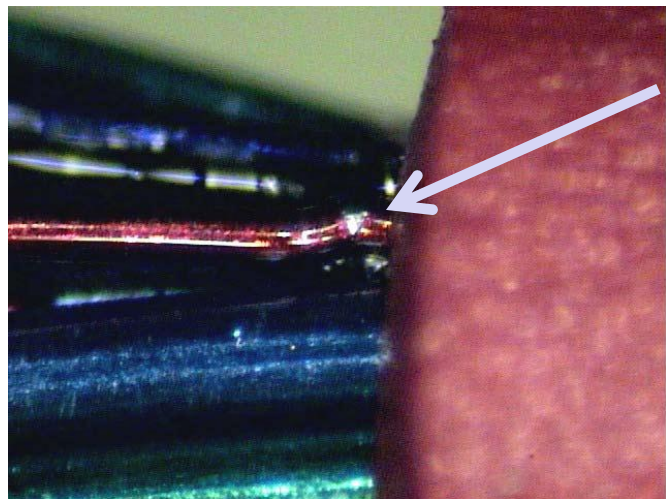
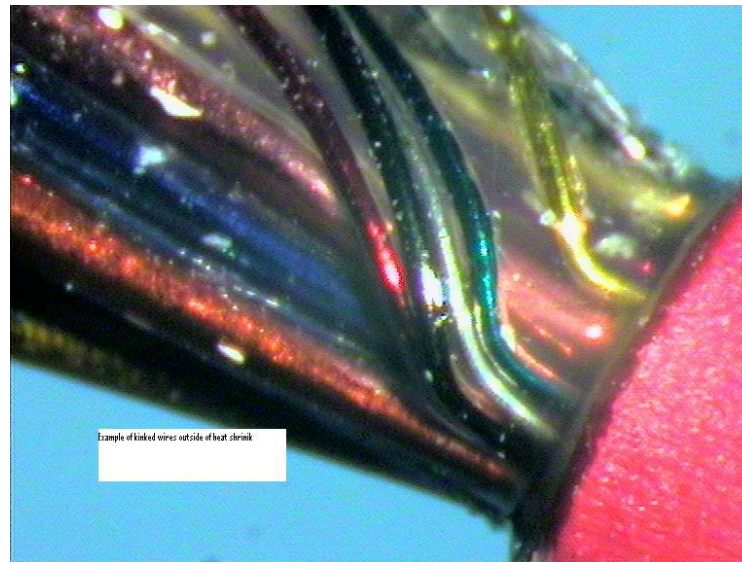
- Problems with connectors of micro-cables:
 - Soldering of the connector broke mainly on the outer pins
 - Had sporadically shown up before, but no systematic stress-tests done, only repair of defect connectors
→ continued to show-up
- Type-0 cable problems (barrel):
 - Discovered during integration
 - Went back to vendor for change of production sequence
 - Scrupulous test program for new cables
- HV return:
 - Tests were blind to a defect in the HV return due to parasitic current paths
 - Problems were found and had to be repaired during installation



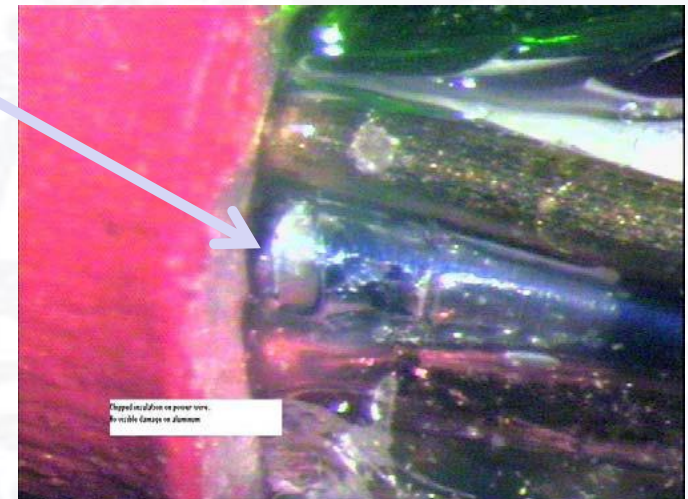
- Connectors at both ends
(mounted on PCB board)
- Round Al conductors
 - 30 individual wires per cable
 - 16 x 100µm diameter
 - 14 x 300 µm diameter
 - Custom thickness polyurethane insulation

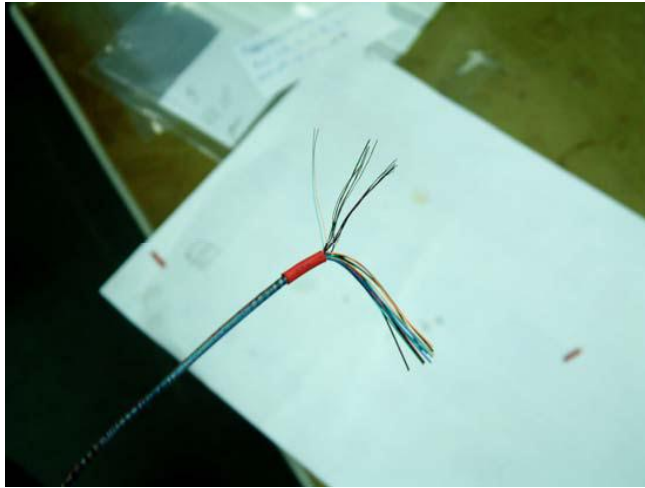


Close-up of a typical cable
Close to heat shrink tube:



Example of damaged
cables: the insulation is
broken, leaving the cable
very vulnerable to failure
with even very delicate
handling or with thermal
cycling





- Wires were bent before stripping, separating thin and thick wires (to be stripped in two different phases)
- Stripping solution is molten NaOH ($T \sim 400^\circ\text{C}$)
- Pictures of insulation heated above 250°C :

Bent then heated:

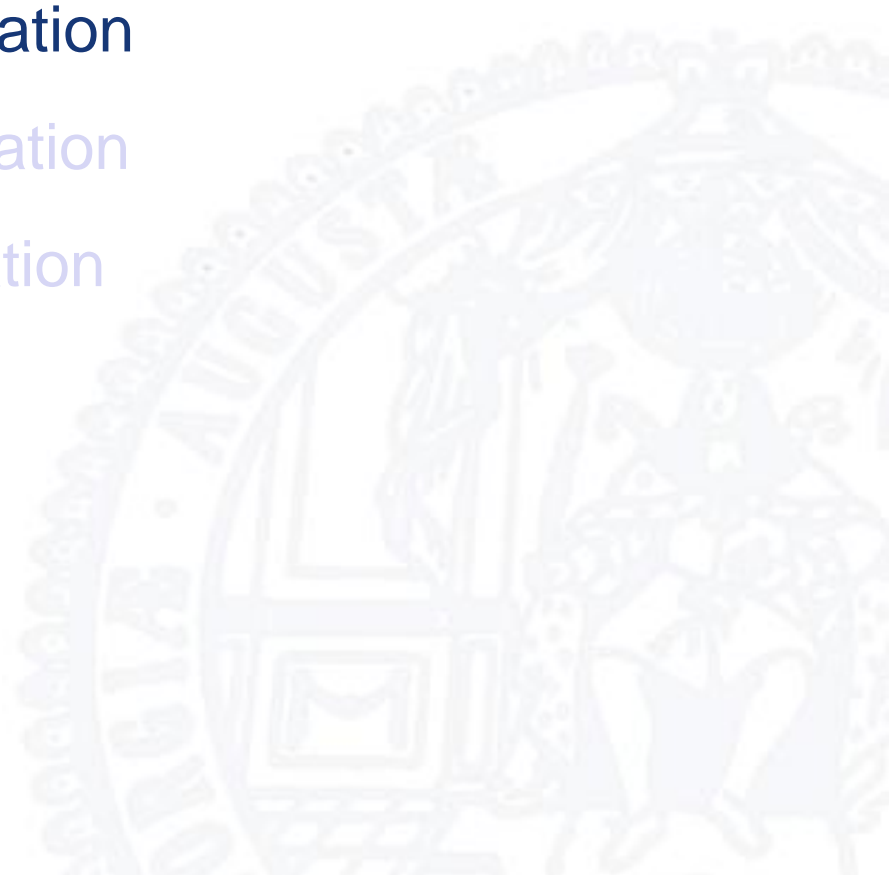


Heated then bent:

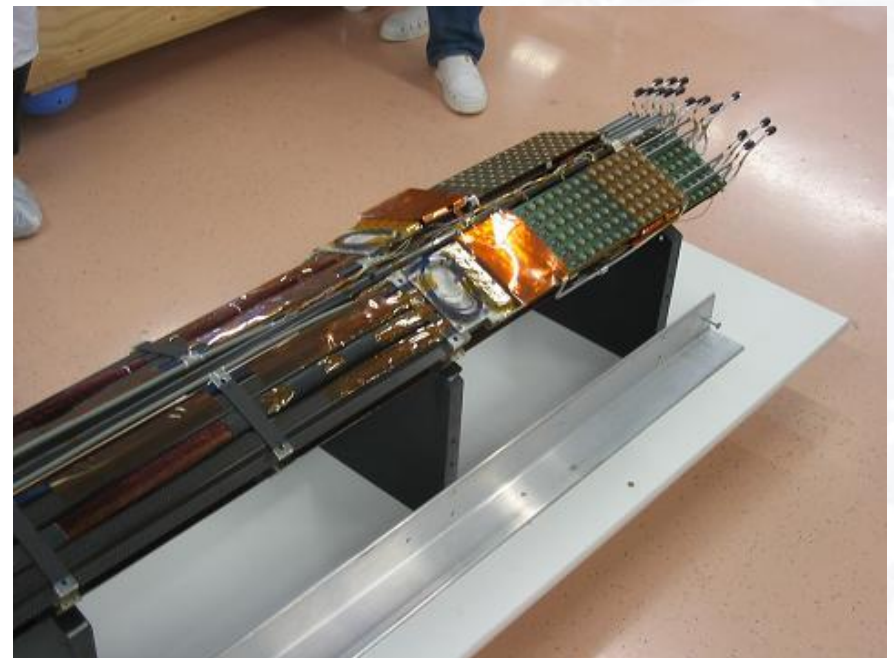
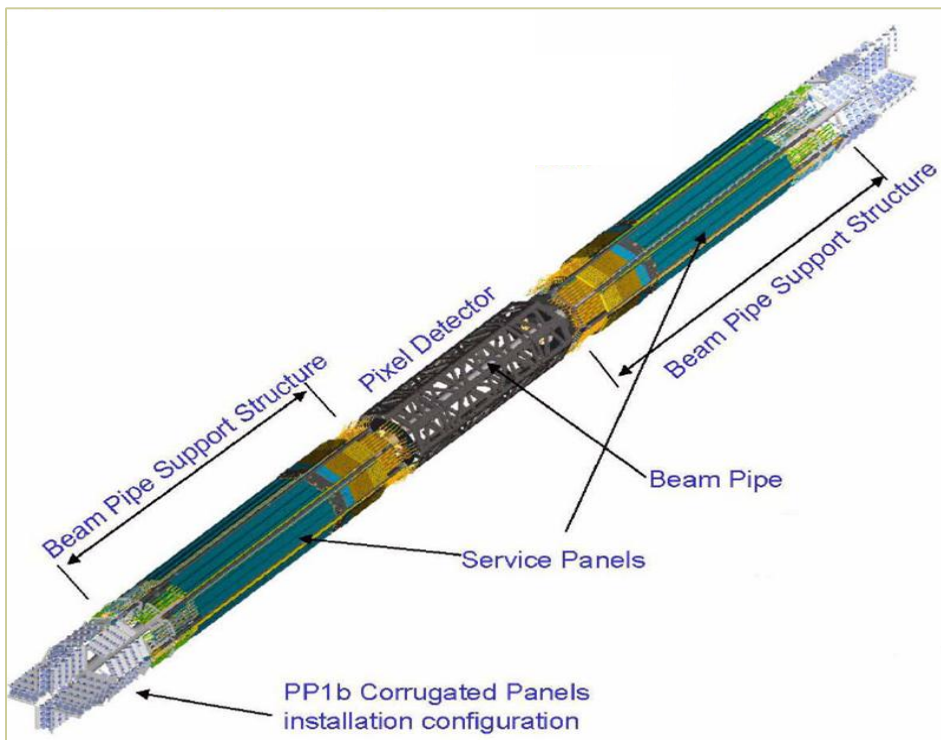


- Reproduced enough cables for layer-0, layer-1 and part of layer-2
- For rest of layer-2 accepted part of initial production after stricter quality control
 - Mechanical stress testing
 - Electrical test and visual inspection before and after stress testing
- After that only very few failures of type-0 cables and not clearly related to the old failure mode

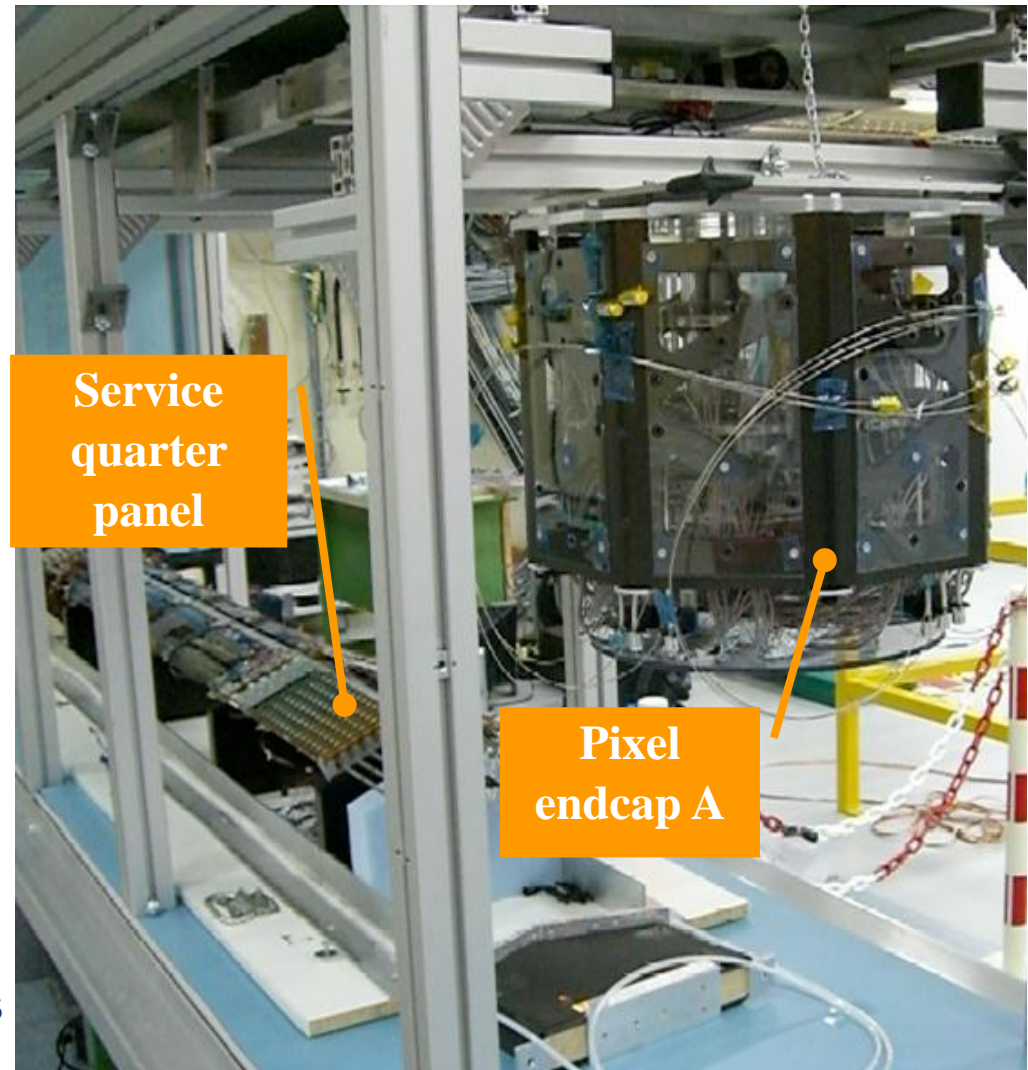
- Pixel Detector Integration
- Pixel Package Integration
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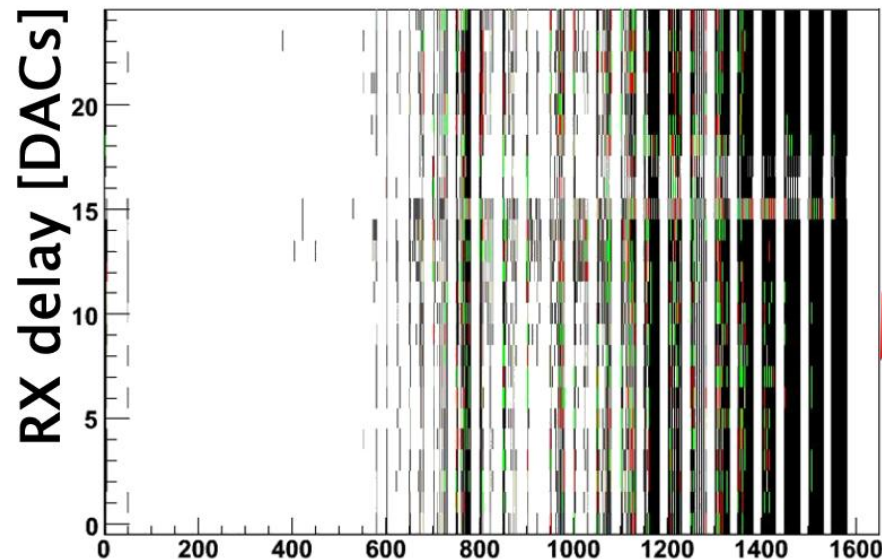
- Service Panels bring services out of inner detector volume (cryostat)
- 7-m-long pixel package integrated on the surface
- Detector plus 8 service quarter panels



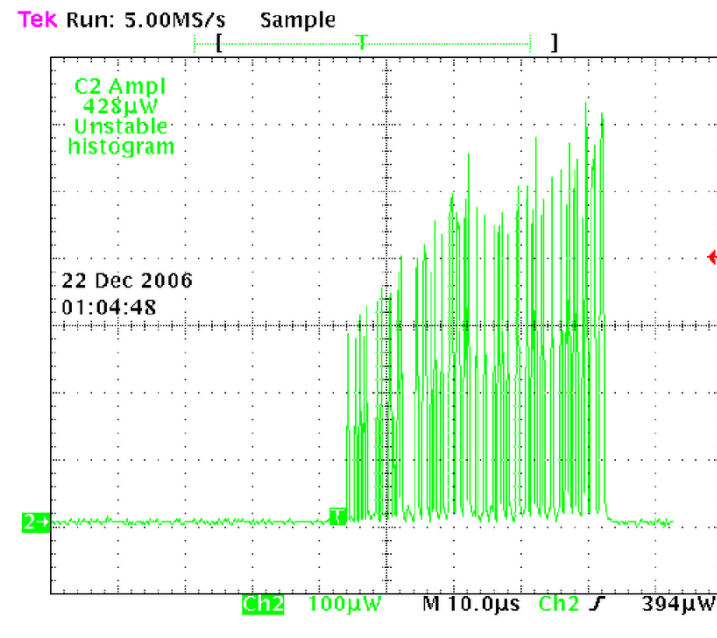
- In fall 2006 – before final detector integration: performed a 10% system test
 - One end-cap (144 modules)
 - One prototype service panel
 - Services and readout close to final version
 - operation at $-10\text{ }^{\circ}\text{C}$, using evaporative cooling;
- Achievements:
 - Commission services
 - Commission DAQ and offline with cosmic and random triggers.
 - Caught several important problems (next slides)



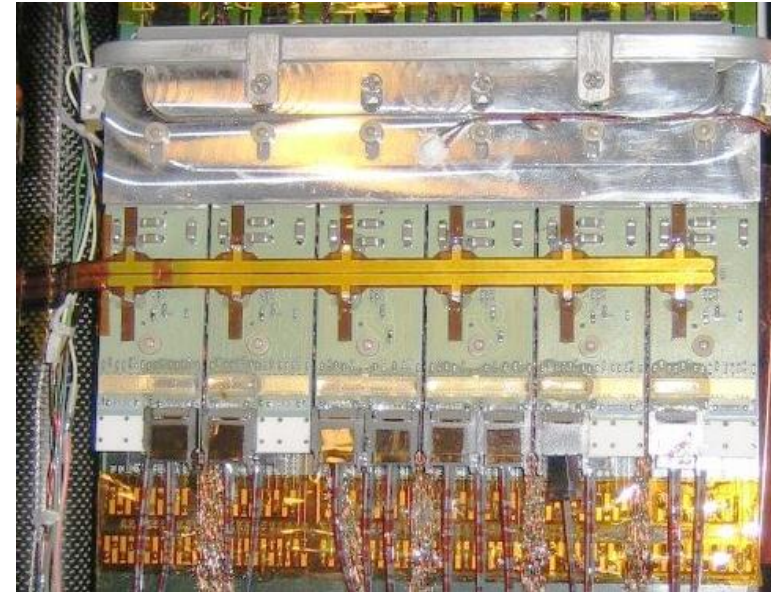
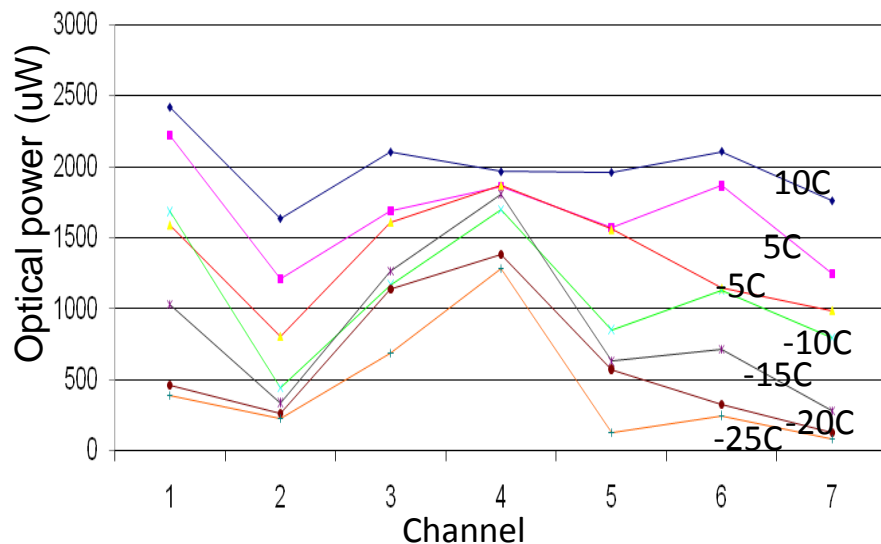
Decoded data-stream:



Scope picture:



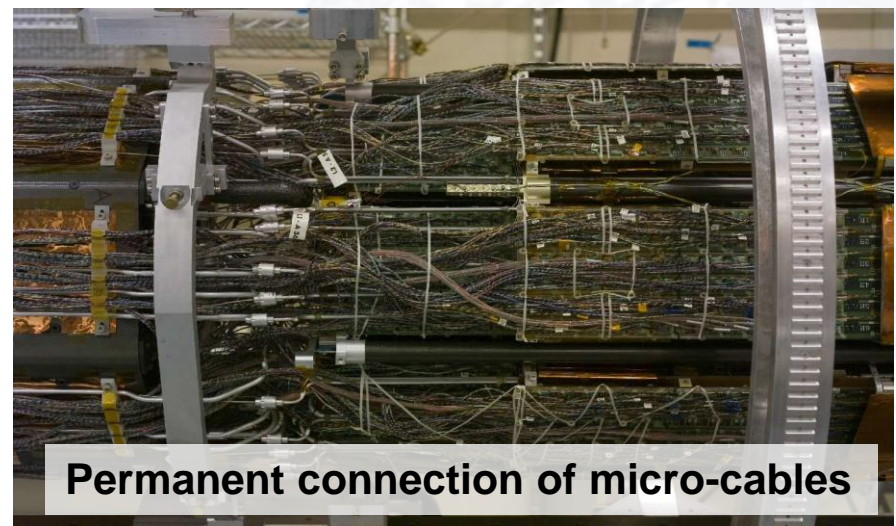
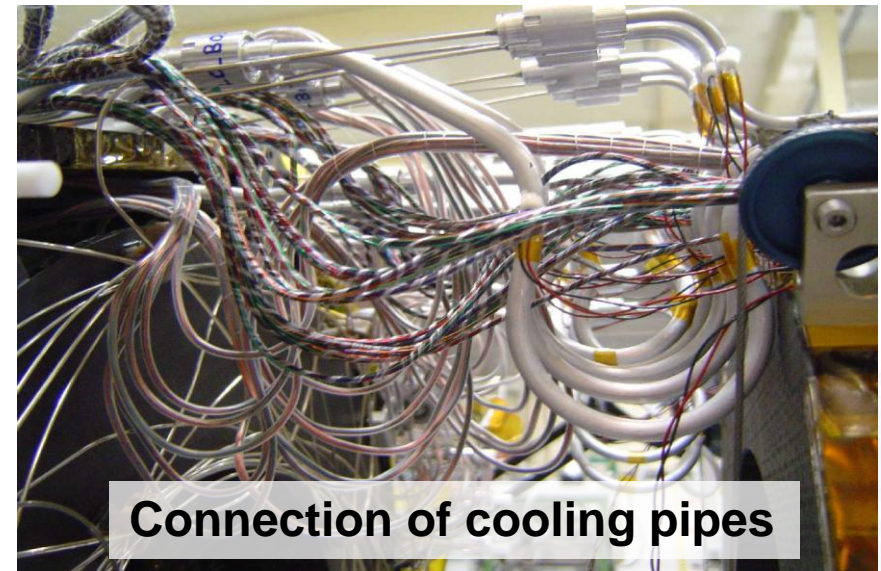
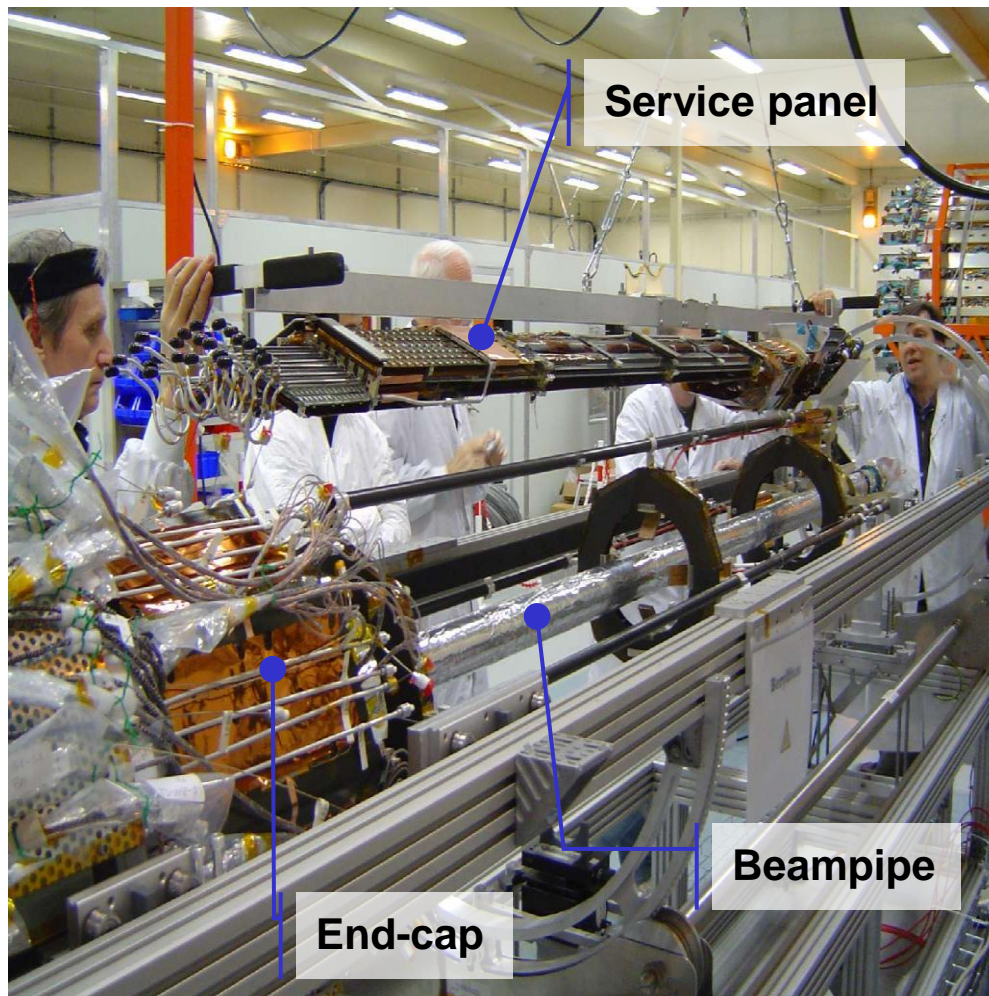
- Problem I: Discovered opto-board channels with slow turn-on
 - Would have led to data corruption during operation
 - Added additional QA step for the opto-boards in the final service quarter panels
 - Several opto-boards with slow turn-on found and exchanged



- Problem II: VCSEL array power and uniformity are temperature dependent
 - One VCSEL array serves 6/7 modules; no single-channel adjustment possible
 - Opto-boards coupled to cooling → added resistive heaters to actively control temperature; now opto-boards are operated at 20degC, all links are tunable
 - Without heaters this problem would have had the potential to make several links in the detector untunable (1 link = 1 module)

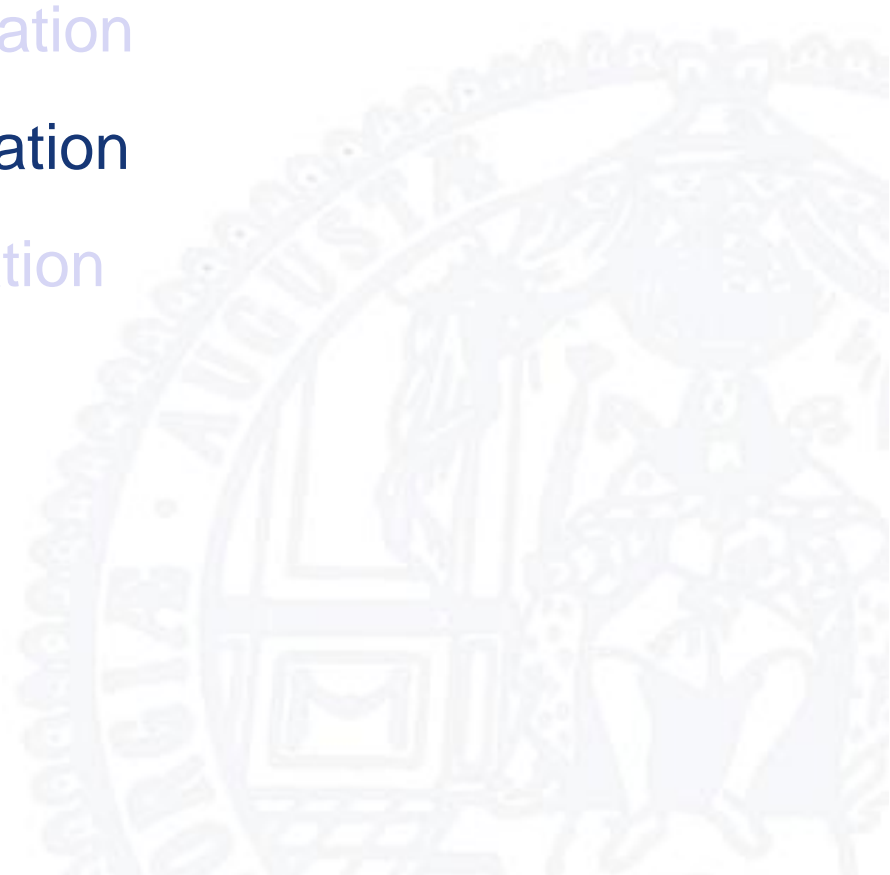
- While setting up system test: Found problem with LEMO-F connectors at PP1 (end of cryostat, point of final connection in the pit)
 - Not exactly the usual cm/inch problem but nearly
 - All components had passed QC but ...
 - Male Lemo-F connectors on the upstream cables (made in collaboration with LEMO-Europe) have movable pins to allow for self-alignment
 - Female Lemo-F connectors in the pixel package (made in collaboration with LEMO-US) were backfilled and thence had fixed pin-receptacles
 - In case of misalignment the receptacle would push the pin back
 - Developed special tool with LEMO to check for vulnerable pins
 - Find, repair and reinforce those pins
 - Check each single pin during service tests
 - Introduce procedure in power-up that checks for open sense lines

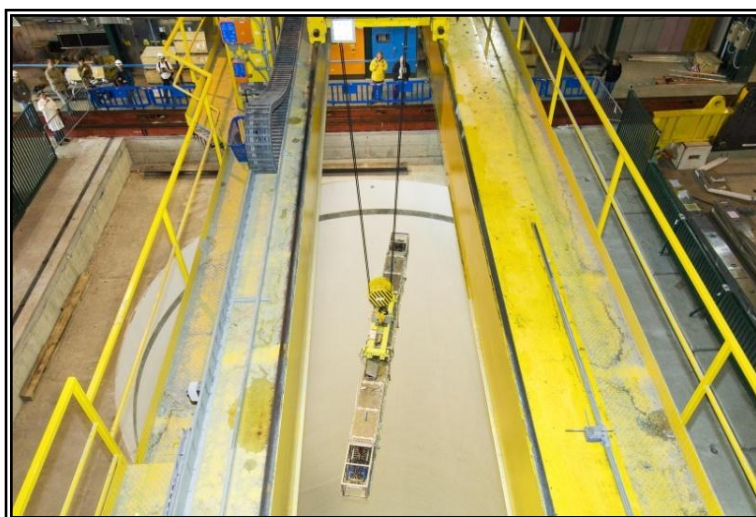
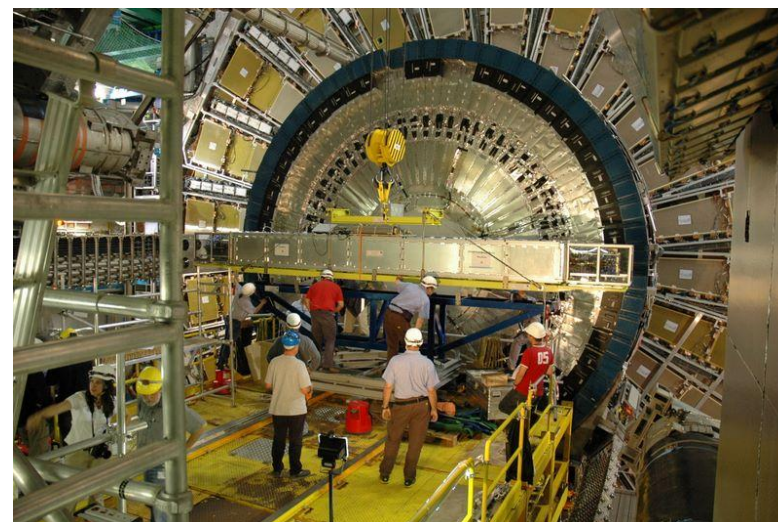




- During integration: connectivity test
 - No module cooling available
 - Develop test procedure that allows to test all connections in the integrated package without overheating the modules
 - Electrical Services (low voltage, high voltage, NTCs)
 - Optical Links (TTC links, data links)
 - Module Functionality and Identity (from threshold dispersion in short threshold scan)
 - Test was performed after connection of each SQP
 - One dead PiN diode channel and one dead VCSEL channel were not followed up; now there are a few more ☹
 - Test was repeated in the pit after the final connection at PP1

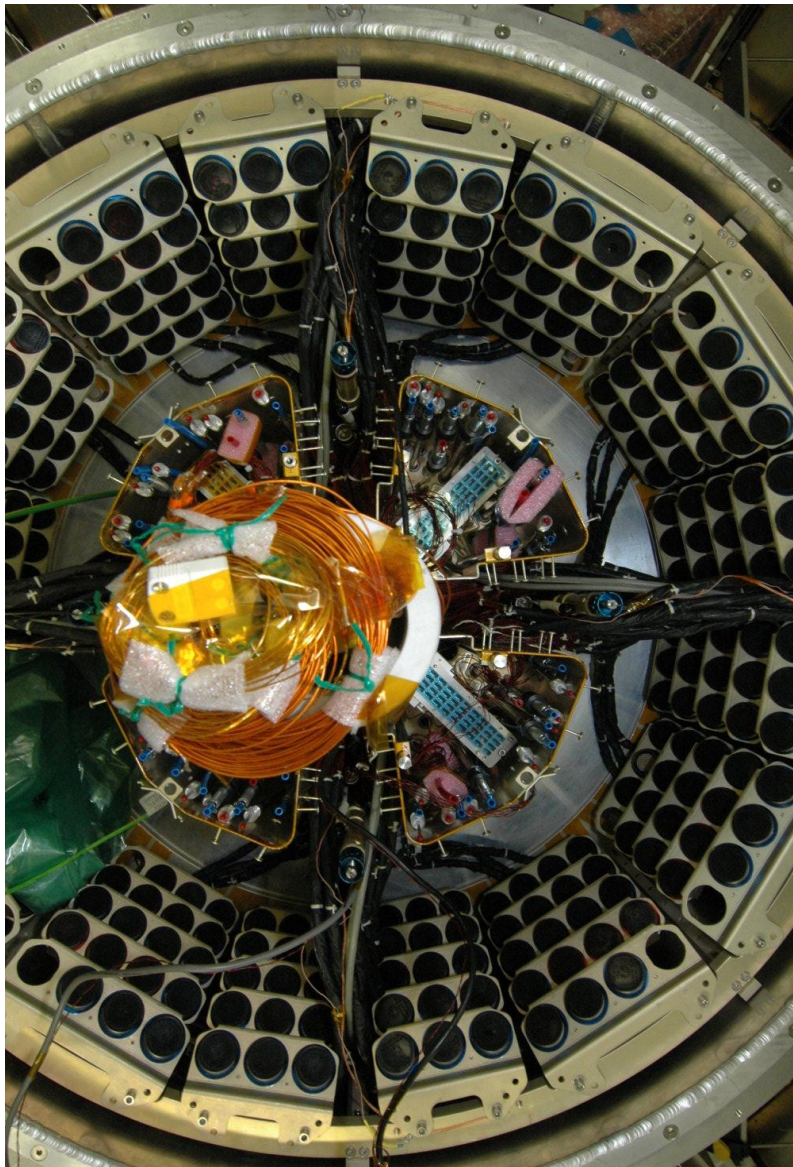
- Pixel Detector Integration
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- Different possibilities to address reliability question
 - In ATLAS: high granularity of services and control
 - 25000 electrical contacts in more than 400 64-pin connectors at PP1
 - 88 independent cooling circuits
 - 588 optical fibre ribbons
 - Large effort spent on testing the services before doing the final connections and verifying the correct connection afterwards
 - Service tests
 - Connectivity test

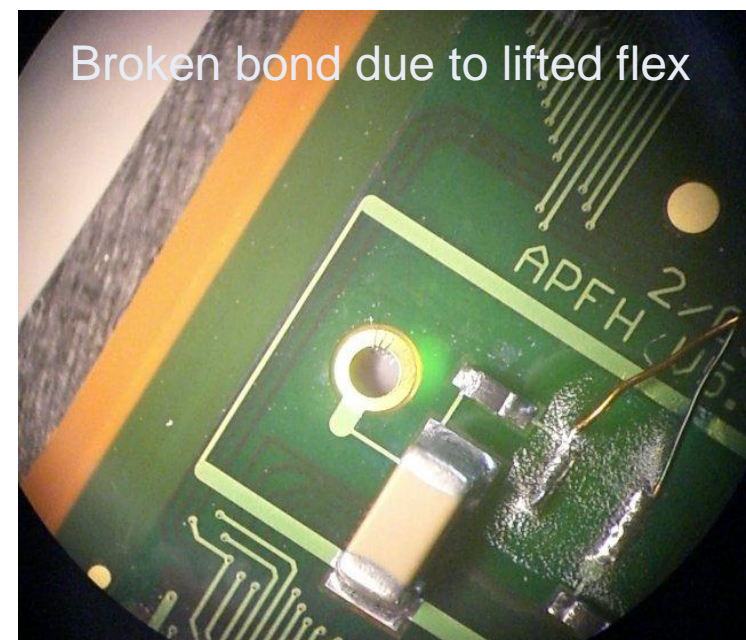
- Service tests:
 - Automated test setup using a switching matrix and a programmable load
 - Connects to services at PP1 (point of final connection)
 - Mimics a group of pixel detector modules and tests
 - Correct connection of all electrical services
 - Correct functioning of hardware interlocks
 - Robustness against sense line breaking (i.e. no dangerous voltages)
 - Correct mapping in the FSM
 - Fibre integrity checked with OTDR measurements
 - Leak tests done on all cooling pipes
 - Guaranteed that services were perfect when connecting the detector
 - Had to exchange parts that had been tested OK before transport and installation



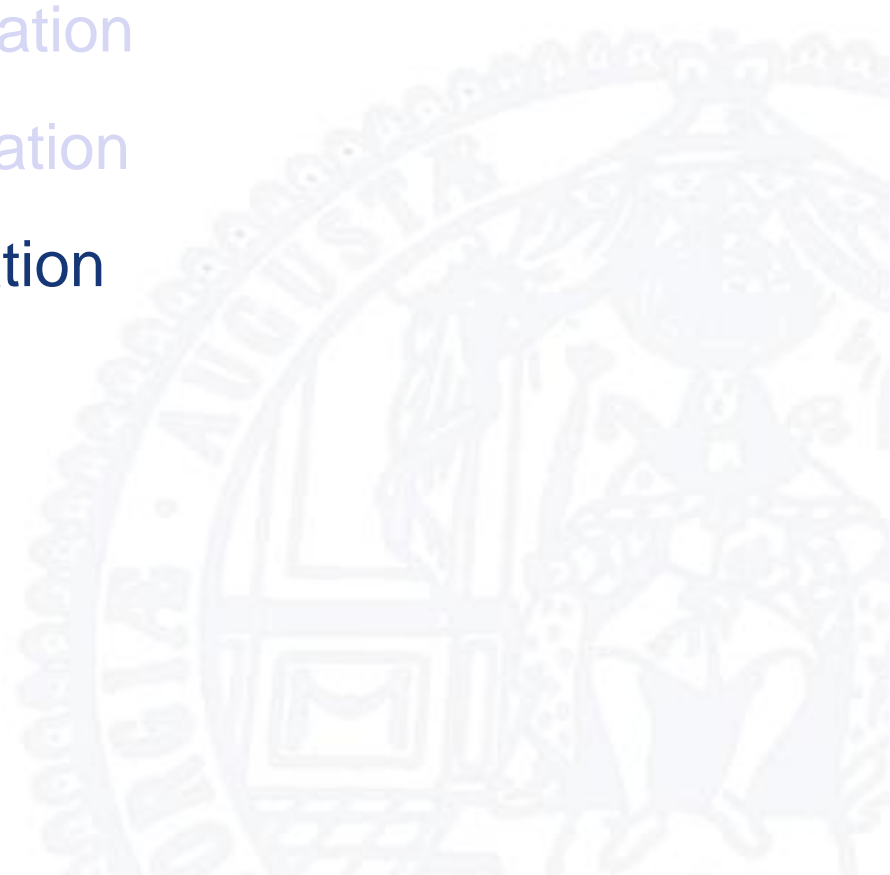
~ 8 wks



- Connectivity test after installation found
 - Aforementioned problem with HV return; could be bypassed
 - 11 unrecoverable modules
- HV Opens are responsible for majority of unrecoverable modules after installation
- At this point not possible to distinguish between cable and wire-bond problem
- Wire-bonds had low intrinsic reliability so that even after QA some weak parts got through
- Might argue that QC was not strict enough

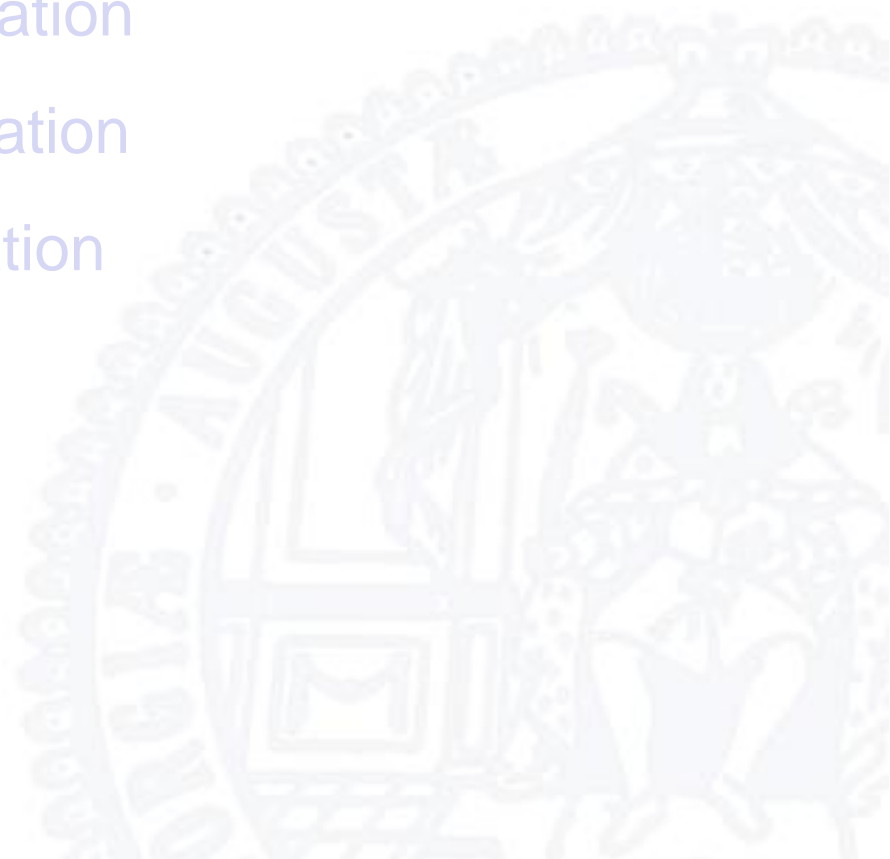


- Pixel Detector Integration
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- During operation in 2008 and early 2009 single laser channels transmitting clock and commands to the detector failed
- Evidence pointed to ESD damage and a new batch with stronger precautions was ordered and installed
- Lasers started to fail again in 2010; most likely cause humidity in the counting room air
- Standard 85/85 test (85C, 85% RH) would probably have revealed the problem
- Luckily no serious problem for operation as laser-plugins can be promptly replaced

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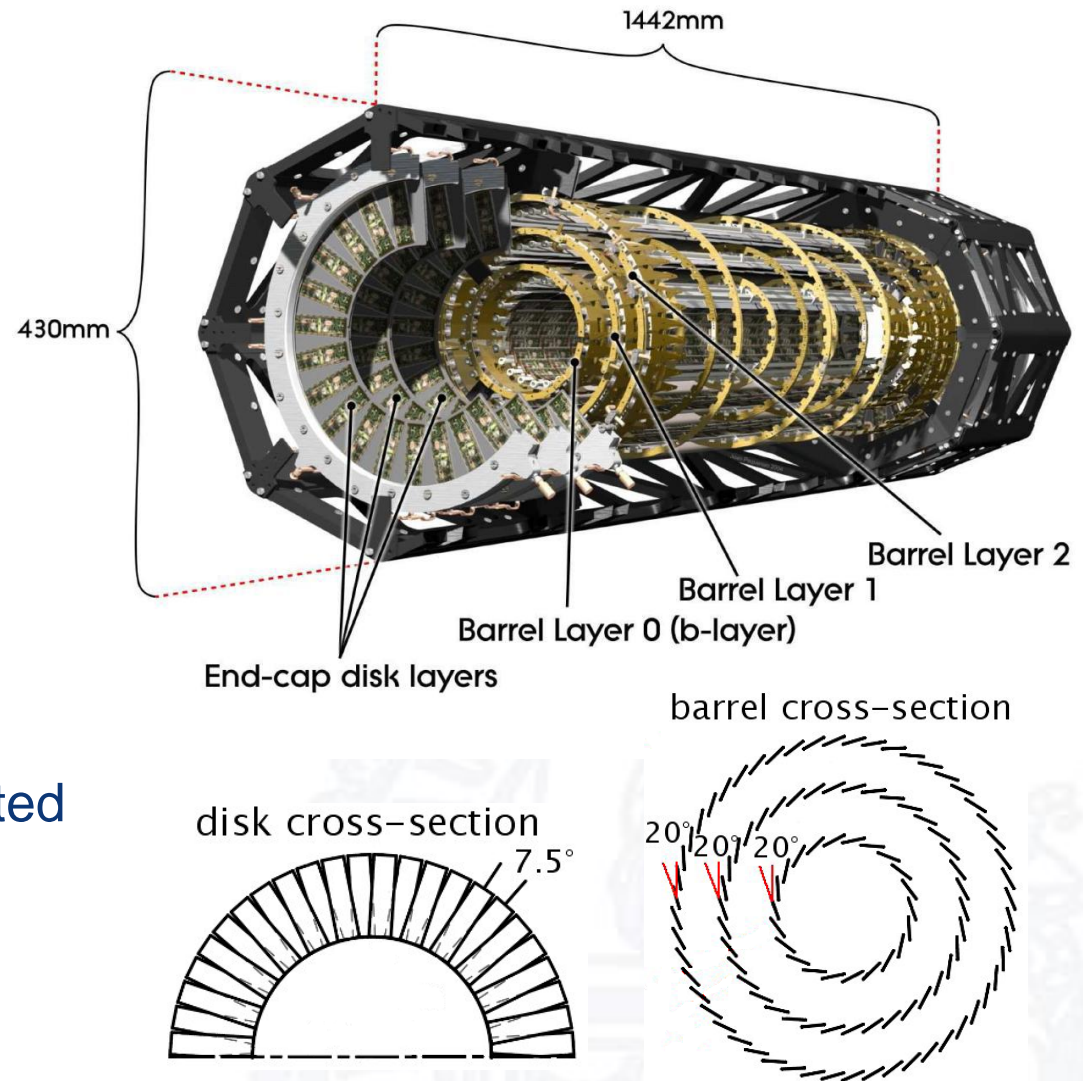
- Quality control during integration and installation revealed several problems which otherwise might have cost us dear
- As a result currently ~97% of the ATLAS Pixel Detector are working and behaving as expected
- Will try to summarise a few lessons we have learned
 - Part of them created some nuisance in getting to the 97%
 - Part of them might be responsible for (at least a fraction of) the 3%

- (Not necessarily new) Lessons we learned:
 - Very often it is the less “sexy” things that fail most
 - In systems built at the extreme limits of material budget etc. there hardly is any component too simple to fail
 - In a large scale system operated over many years, there are hardly any one-time failures; even problems that seem “singular” during production and testing might be worth being followed up
 - Test each piece as long as possible under as realistic conditions as possible; a system test is an invaluable instrument to spot problems that occur only when the different pieces have to work together
 - In areas where expertise within the HEP community is limited: be conservative in design, adopt standard test procedures

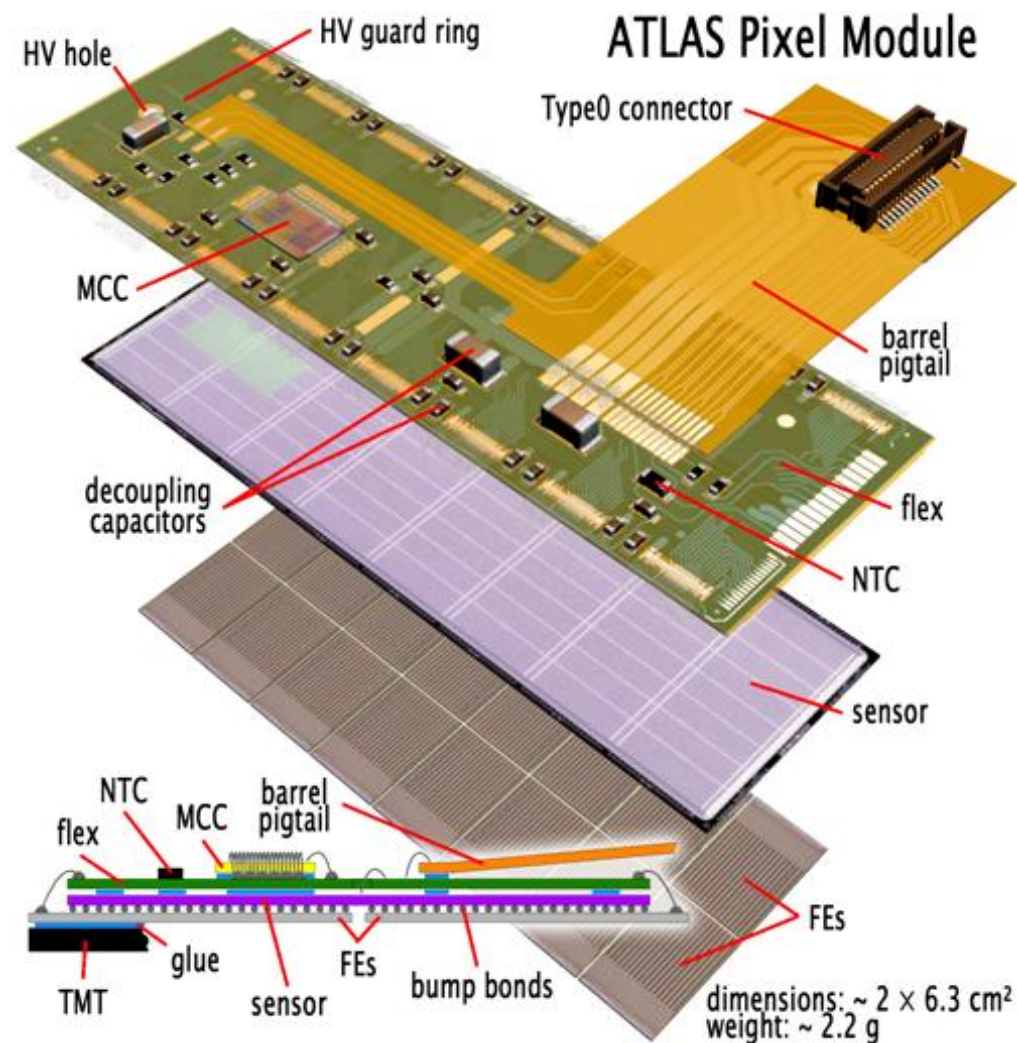
- Backup

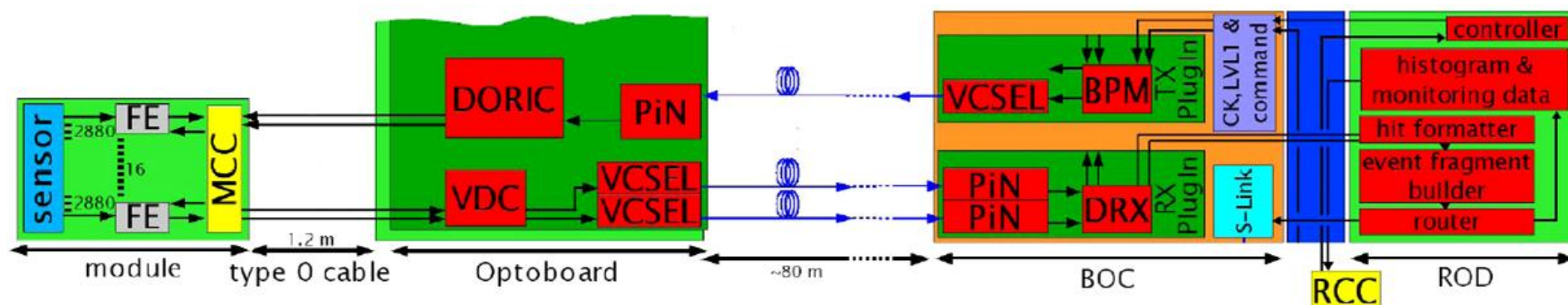


- 3 hit-system for $|\eta| < 2.5$
 - 3 barrel layers
 - 2 x 3 endcap discs
- 1744 modules,
80M readout channels
- Innermost barrel layer at 5 cm
 - Radiation tolerance
 $500 \text{ kGy} / 10^{15} \text{ 1MeV } n_{\text{eq}} \text{ cm}^{-2}$
- Evaporative C3F8 cooling integrated
in local support structures
 → Module temperatures $< 0^\circ\text{C}$
 (Average temperature -13°C ,
 warmest module at -5°C)



- Sensor:
 - 250 μm thick n-on-n sensor
 - 47232 (328 x 144) pixels
 - Typical pixel size 50 x 400 μm^2
(50 x 600 μm^2 pixels in gaps between FE chips)
 - Bias voltage 150 – 600 V
- Readout:
 - 16 FE chips, 2880 pixels each
 - Zero suppression in the FE chip, MCC builds module event
 - Pulse height measured by means of Time over Threshold
 - Data transfer 40 – 160 MHz depending on layer





- Data to and from the detector is transmitted over optical links
- Electro-optical conversion is done
 - On-detector in the optoboards, ~ 1m from the IP
 - Off-detector in the readout crates (back-of-crate cards)
- Optical link tuning:
 - Mainly adjustment of the parameters of the Rx(data)-link